

Application/Control No.	Applicant(s)/Patent under Reexamination
10/049,822	OHTA ET AL.
Examiner	Art Unit
Christopher H. Yaen	1643

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Stic SEQ. ID No: 1-2, 12- 13		4/2/2007	СНҮ	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
updated searches	4/2/2007	СНҮ	
palm database search	4/2/2007	СНҮ	
stic SEQ. ID No: 1,2 12, 13	4/2/2007	СНҮ	
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